Semiconductor Device Test Set - Page 1 of 1



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Width:
4.250 inches
Length:
5.500 inches
Joint Electronics Type Designation System Item Name:
Test set, semiconductor device
Joint Electronics Type Designation System Item Type Number:
Ts-3253/tpm-39
Material And Location:
Aluminum housing
Inclosure Feature:
Single item w/housing
Test Type For Which Designed:
Microwave diode current
Operating Test Capability:
Microamphere meter range 0-1000 ua dc
Height:
3.880 inches
Surface Treatment:
Enamel
Surface Treatment:
Enamel
Fsc Application Data:
Test set, elect. Equip.
Shelf Life:
N/a
Unit Of Measure:
Demilitarization:
No
Fiig:
T228-a